Search Notes

| Application/Control No. | Applicant(s)/Patent Under Reexamination |
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| 10666862 | SMIT ET AL. |
| Examiner | Art Unit |
| HIEP NGUYEN | 3686 |

| SEARCHED | | | |
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| Class | Subclass | Date | Examiner |
| 705 | 03 | 10/20/2008 | HN |

| SEARCH NOTES | | |
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| Search Notes | Date | Examiner |
| Search EAST- See sattached search history | 10/20/2008 | HN |

| INTERFERENCE SEARCH | | | |
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U.S. Patent and Trademark Office Part of Paper No. : 20081017